## $\square$ MN101E56 Series

| Type | MN101EF56G |
| :--- | :---: |
| Internal ROM type | FLASH |
| ROM (byte) | 128 K |
| RAM (byte) | 6 K |
| Package (Lead-free) | LQFP100-P-1414, QFP100-P-1818B |
| Minimum Instruction <br> Execution Time | $50 \mathrm{~ns} \mathrm{(at} \mathrm{2.7} \mathrm{~V} \mathrm{to} 5.5 \mathrm{~V}, 20 \mathrm{MHz}$ ) |

## Interrupts

5 external interrupts. 29 internal interrupts
RESET. NMI. External 0 to 4 . Timer 0 to 4 . Timer 6 . Timer 7 ( 2 systems). Timer 8 ( 2 systems). Timer 9 ( 3 systems). Time base. 24H timer. Alarm. Serial 0 ( 2 systems). Serial 1 ( 2 systems). Serial 2 ( 2 systems). Serial 4 ( 2 systems). LIN. A/D conversion. ATC. Key interrupt. Low voltage detection

- Timer Counter

8 -bit timer $\times 7$
Timer 0 ..................Timer pulse output. Added pulse(2-bit)type PWM output to large current terminal TMOIOB possible. Event count. Simple pulse width measurement
Timer 1 ..................Timer pulse output. Event count. 16-bit cascade connected (timer 0, 1). Timer synchronous output
Timer 2 .................Timer pulse output. Added pulse(2-bit)type PWM output to large current terminal TM2IOB possible. Event count. Simple pulse width measurement. 24-bit cascade connected (timer 0,1,2). Timer synchronous output
Timer 3 ..................Timer pulse output. Event count. 16-bit cascade connected (timer 2, 3). 32-bit cascade connected (timer 0, 1, 2, 3)
Timer 4 .................Timer pulse output. Added pulse (2-bit) type PWM output. Event count. Simple pulse width measurement
Timer 6 ..................8-bit freerun timer
Timer A.................Baud rate timer. Clock output for peripheral function

## 16 -bit timer $\times 3$

Timer 7 $\qquad$ .Timer pulse output to large current terminal TM7IOB possible. Event count. High accuracy PWM/IGBT output (cycle/duty continuous variable). Pulse width measurement. Timer synchronous output. Input capture (both edge available). Real time output control. Double buffer compare register
Timer 8 $\qquad$ .Timer pulse output to large current terminal TM8IOB possible. Event count. High accuracy PWM output (cycle/duty continuous variable). Pulse width measurement. Input capture (both edge available). 32-bit cascade connected (timer 7, 8). 32-bit PWM output. Synchronous output event. Double buffer compare register
Timer 9 $\qquad$ Timer pulse output to large current terminal TM9IOB possible. 3-phase PWM output. Triangular waveform output. Jigsaw waveform output. Dead time setup. Event count
24H timer: Interval function (Interruption every 0.5 seconds, every 1 second, every 1 minute, every 1 hour and 24 hours). Alarm function Time base timer: One-minute count setting
Watchdog timer $\times 2$

## Serial interface

Synchronous type/UART (full-duplex)/LIN $\times 1$ : Serial 0
Synchronous type/UART (full-duplex) $\times 2$ : Serial 1, 2
Synchronous type/Multi-master I ${ }^{2} \mathrm{C} \times 1$ : Serial 4

- DMA controller

1 systems. Maximum transfer cycles are 255
Starting factor: External request. Internal event. Software

## ■ I/O Pins

90 : Common use. Specified pull-up/pull-down resistor available. Input/output selectable (bit unit)

## A/D converter

10 -bit $\times 24$ channels

- D/A converter

8 -bit $\times 4$ channels
■ Display control function
LCD: 55 segments $\times 4$ commons (Static, $1 / 2,1 / 3$, or $1 / 4$ duty)
Usable if VLC1 $\leq$ VDD

## Special Ports

Buzzer output. Inverted buzzer output. High-current drive port

- Reset

Low voltage detection. Automatic Reset. Reset factor detection

- Internal oscillation

High speed: $20 \mathrm{MHz} / 16 \mathrm{MHz}$. Low speed: 30 kHz

- Pin Assignment

LQFP100-P-1414, QFP100-P-1818B


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